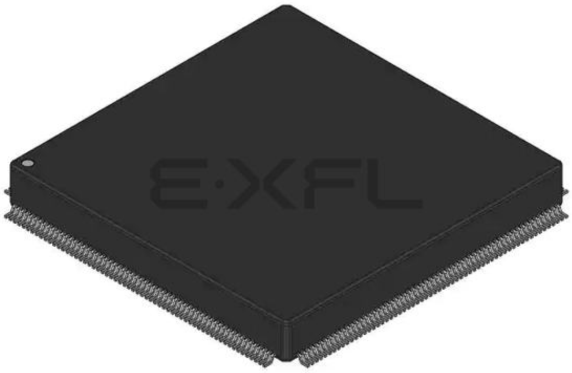
Altera - EPM9400RC240-20 Datasheet



Understanding Embedded - CPLDs (Complex Programmable Logic Devices)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

Applications of Embedded - CPLDs

Details	
Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	20 ns
Voltage Supply - Internal	4.75V ~ 5.25V
Number of Logic Elements/Blocks	25
Number of Macrocells	400
Number of Gates	8000
Number of I/O	159
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	240-BFQFP
Supplier Device Package	240-RQFP (32x32)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=epm9400rc240-20

The MAX 9000 family is supported by Altera's MAX+PLUS II development system, a single, integrated software package that offers schematic, text—including VHDL, Verilog HDL, and the Altera Hardware Description Language (AHDL)—and waveform design entry, compilation and logic synthesis, simulation and timing analysis, and device programming. The MAX+PLUS II software provides EDIF 200 and 300, LPM, and other interfaces for additional design entry and simulation support from other industry-standard PC- and UNIX-workstation-based EDA tools. The MAX+PLUS II software runs on Windows-based PCs as well as Sun SPARCstation, HP 9000 Series 700/800, and IBM RISC System/6000 workstations.

For more information on development tools, see the *MAX+PLUS II Programmable Logic Development System & Software Data Sheet*.

Functional Description

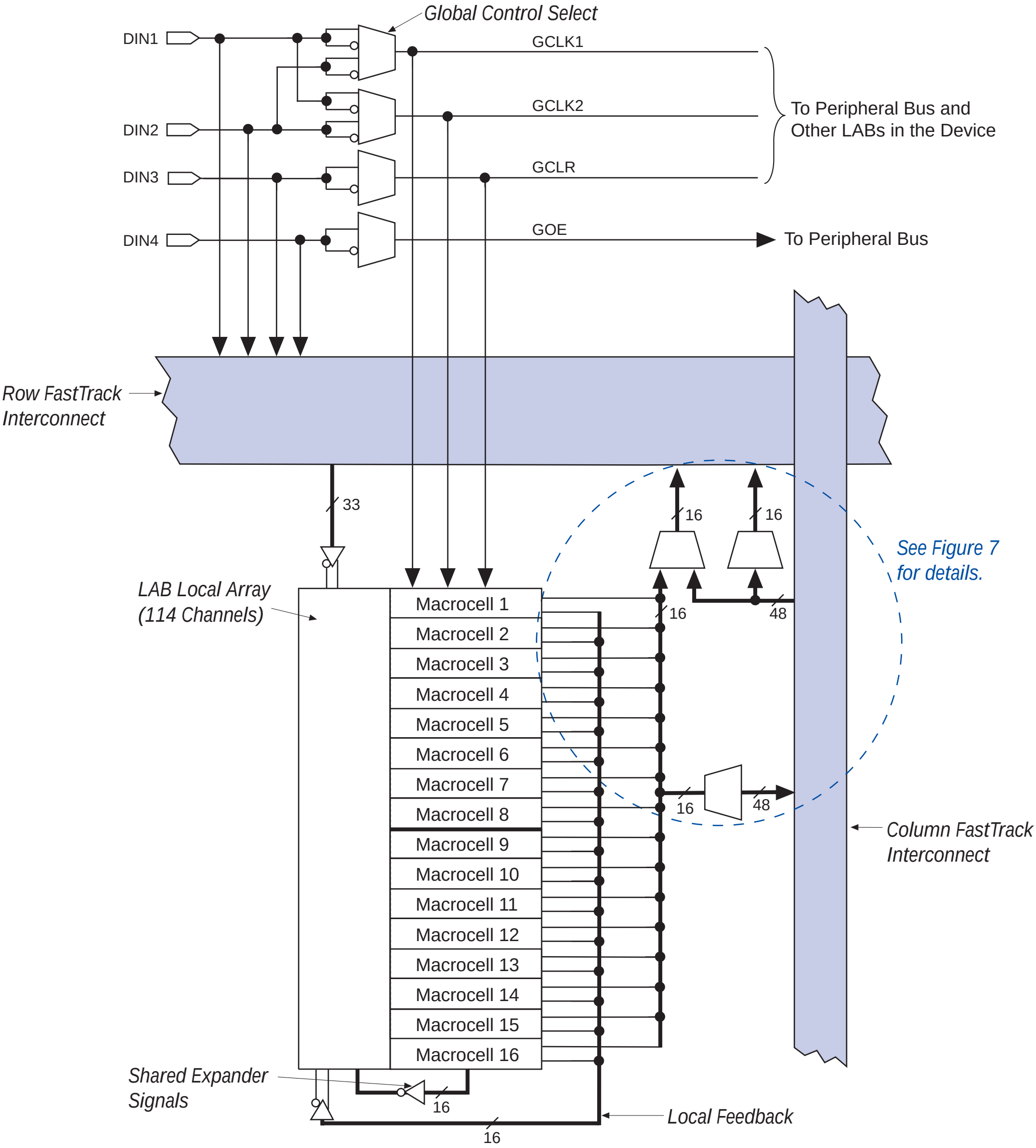
MAX 9000 devices use a third-generation MAX architecture that yields both high performance and a high degree of utilization for most applications. The MAX 9000 architecture includes the following elements:

- Logic array blocks
- Macrocells
- Expander product terms (shareable and parallel)
- FastTrack Interconnect
- Dedicated inputs
- I/O cells

Figure 1 shows a block diagram of the MAX 9000 architecture.

LABs drive the row and column interconnect directly. Each macrocell can drive out of the LAB onto one or both routing resources. Once on the row or column interconnect, signals can traverse to other LABs or to the IOCs.

Figure 2. MAX 9000 Logic Array Block



For registered functions, each macrocell register can be individually programmed for D, T, JK, or SR operation with programmable clock control. The flipflop can also be bypassed for combinatorial operation. During design entry, the user specifies the desired register type; the MAX+PLUS II software then selects the most efficient register operation for each registered function to optimize resource utilization.

Each programmable register can be clocked in three different modes:

- By either global clock signal. This mode achieves the fastest clock-to-output performance.
- By a global clock signal and enabled by an active-high clock enable. This mode provides an enable on each flipflop while still achieving the fast clock-to-output performance of the global clock.
- By an array clock implemented with a product term. In this mode, the flipflop can be clocked by signals from buried macrocells or I/O pins.

Two global clock signals are available. As shown in Figure 2, these global clock signals can be the true or the complement of either of the global clock pins (`DIN1` and `DIN2`).

Each register also supports asynchronous preset and clear functions. As shown in Figure 3, the product-term select matrix allocates product terms to control these operations. Although the product-term-driven preset and clear inputs to registers are active high, active-low control can be obtained by inverting the signal within the logic array. In addition, each register clear function can be individually driven by the dedicated global clear pin (`DIN3`). The global clear can be programmed for active-high or active-low operation.

All MAX 9000 macrocells offer a dual-output structure that provides independent register and combinatorial logic output within the same macrocell. This function is implemented by a process called register packing. When register packing is used, the product-term select matrix allocates one product term to the D input of the register, while the remaining product terms can be used to implement unrelated combinatorial logic. Both the registered and the combinatorial output of the macrocell can feed either the FastTrack Interconnect or the LAB local array.

Parallel Expanders

Parallel expanders are unused product terms that can be allocated to a neighboring macrocell to implement fast, complex logic functions. Parallel expanders allow up to 20 product terms to directly feed the macrocell `OR` logic, with five product terms provided by the macrocell and 15 parallel expanders provided by neighboring macrocells in the LAB. Figure 5 shows how parallel expanders can feed the neighboring macrocell.

Figure 5. MAX 9000 Parallel Expanders

Unused product terms in a macrocell can be allocated to a neighboring macrocell.

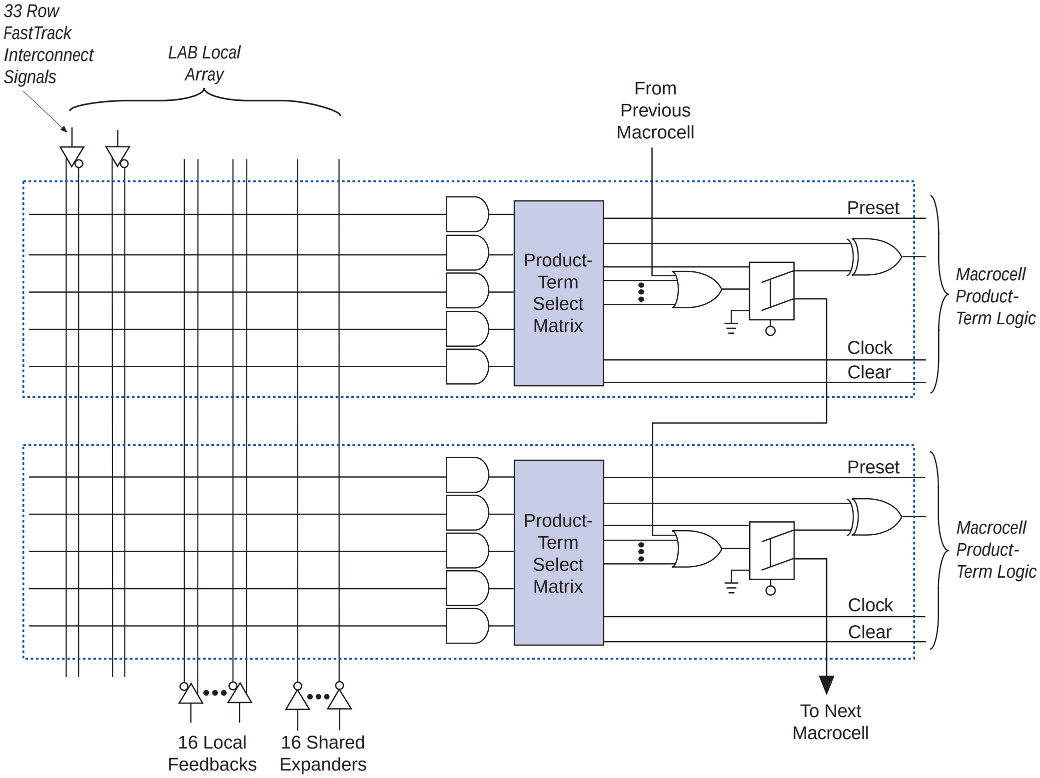
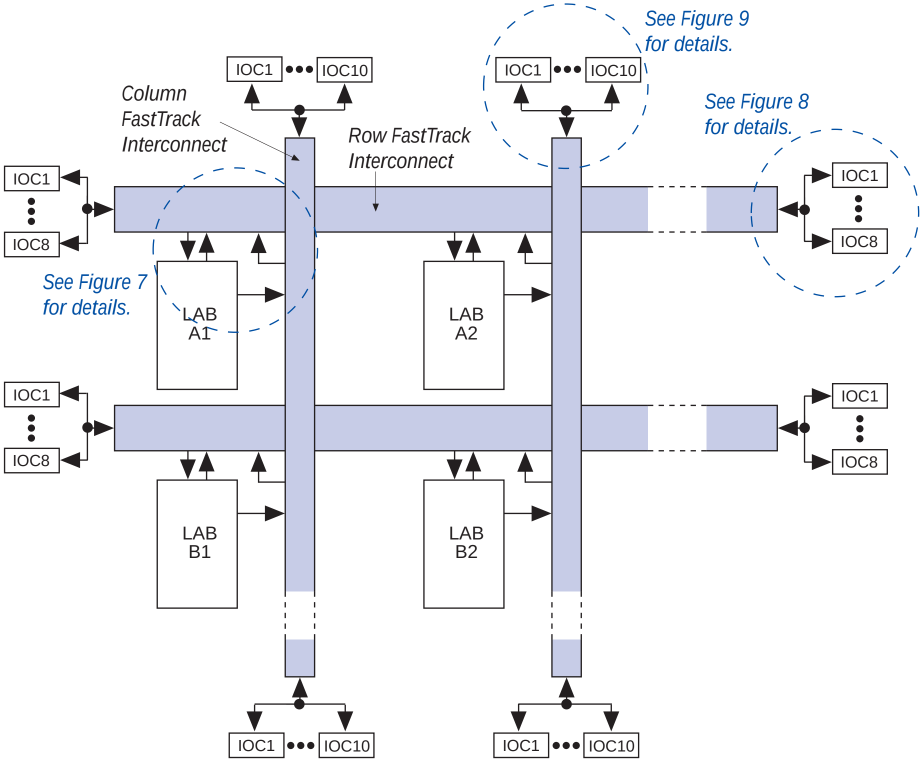


Figure 6. MAX 9000 Device Interconnect Resources

Each LAB is named on the basis of its physical row (A, B, C, etc.) and column (1, 2, 3, etc.) position within the device.



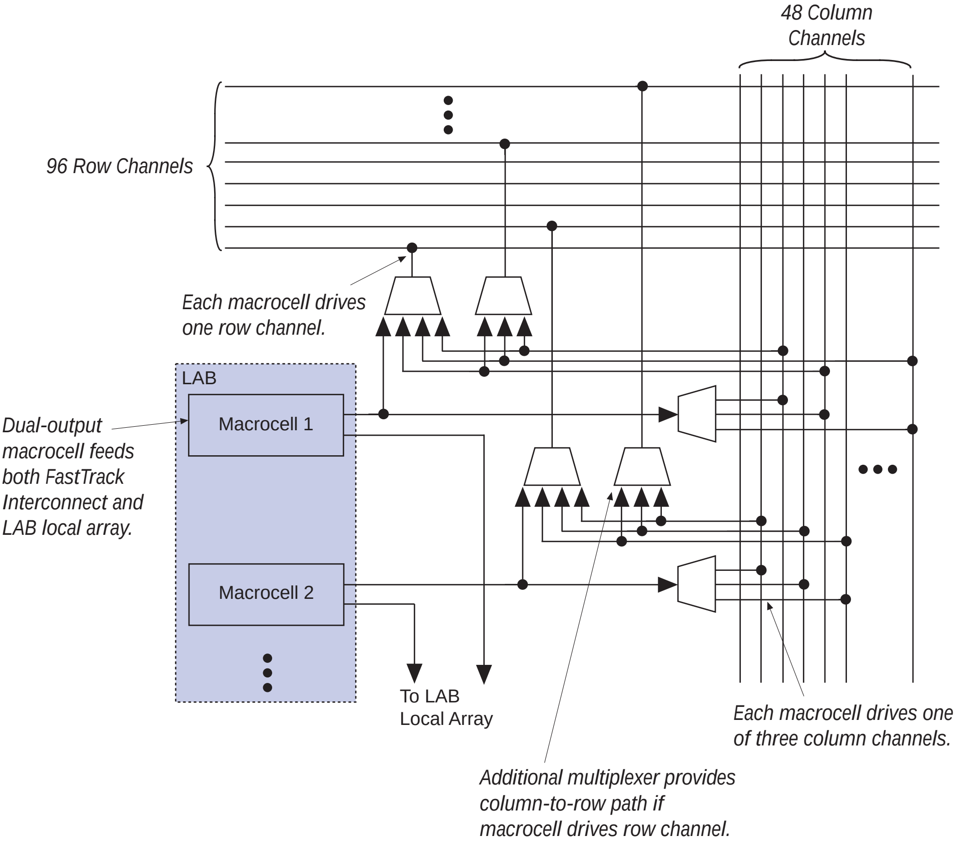
The LABs within MAX 9000 devices are arranged into a matrix of columns and rows. Table 5 shows the number of columns and rows in each MAX 9000 device.

Table 5. MAX 9000 Rows & Columns

Devices	Rows	Columns
EPM9320, EPM9320A	4	5
EPM9400	5	5
EPM9480	6	5
EPM9560, EPM9560A	7	5

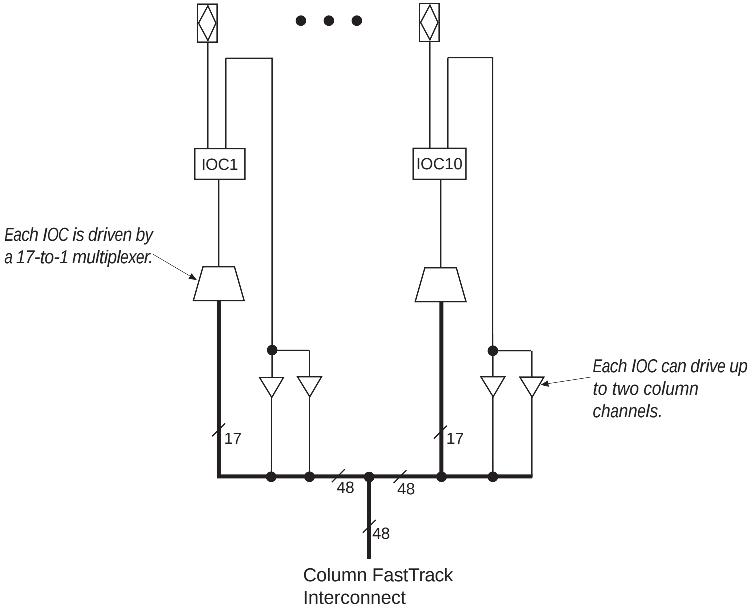
Each row of LABs has a dedicated row interconnect that routes signals both into and out of the LABs in the row. The row interconnect can then drive I/O pins or feed other LABs in the device. Each row interconnect has a total of 96 channels. Figure 7 shows how a macrocell drives the row and column interconnect.

Figure 7. MAX 9000 LAB Connections to Row & Column Interconnect



Each macrocell in the LAB can drive one of three separate column interconnect channels. The column channels run vertically across the entire device, and are shared by the macrocells in the same column. The MAX+PLUS II Compiler optimizes connections to a column channel automatically.

Figure 9. MAX 9000 Column-to-IOC Connections



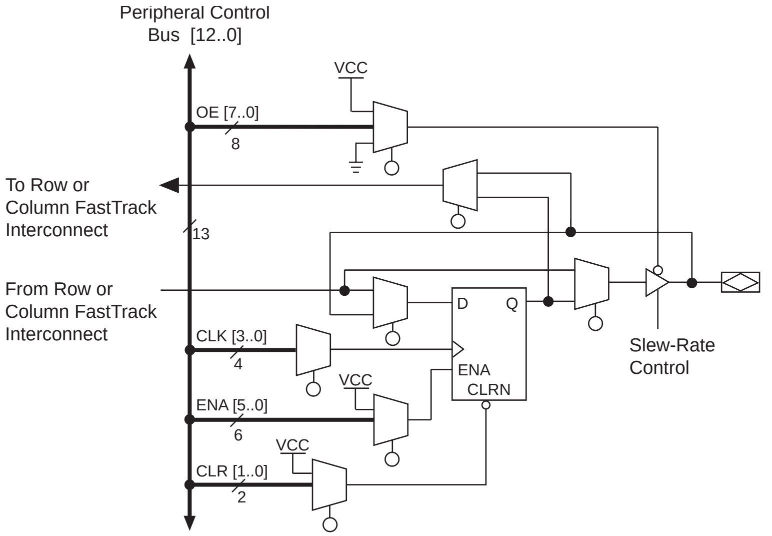
Dedicated Inputs

In addition to the general-purpose I/O pins, MAX 9000 devices have four dedicated input pins. These dedicated inputs provide low-skew, device-wide signal distribution to the LABs and IOCs in the device, and are typically used for global clock, clear, and output enable control signals. The global control signals can feed the macrocell or IOC clock and clear inputs, as well as the IOC output enable. The dedicated inputs can also be used as general-purpose data inputs because they can feed the row FastTrack Interconnect (see Figure 2 on page 7).

I/O Cells

Figure 10 shows the IOC block diagram. Signals enter the MAX 9000 device from either the I/O pins that provide general-purpose input capability or from the four dedicated inputs. The IOCs are located at the ends of the row and column interconnect channels.

Figure 10. MAX 9000 IOC



I/O pins can be used as input, output, or bidirectional pins. Each IOC has an IOC register with a clock enable input. This register can be used either as an input register for external data that requires fast setup times, or as an output register for data that requires fast clock-to-output performance. The IOC register clock enable allows the global clock to be used for fast clock-to-output performance, while maintaining the flexibility required for selective clocking.

The clock, clock enable, clear, and output enable controls for the IOCs are provided by a network of I/O control signals. These signals can be supplied by either the dedicated input pins or internal logic. The IOC control-signal paths are designed to minimize the skew across the device. All control-signal sources are buffered onto high-speed drivers that drive the signals around the periphery of the device. This “peripheral bus” can be configured to provide up to eight output enable signals, up to four clock signals, up to six clock enable signals, and up to two clear signals. Table 6 on page 18 shows the sources that drive the peripheral bus and how the IOC control signals share the peripheral bus.

Programming Sequence

During in-system programming, instructions, addresses, and data are shifted into the MAX 9000 device through the `TDI` input pin. Data is shifted out through the `TDO` output pin and compared against the expected data.

Programming a pattern into the device requires the following six ISP stages. A stand-alone verification of a programmed pattern involves only stages 1, 2, 5, and 6.

1. *Enter ISP*. The enter ISP stage ensures that the I/O pins transition smoothly from user mode to ISP mode. The enter ISP stage requires 1 ms.

2. *Check ID*. Before any program or verify process, the silicon ID is checked. The time required to read this silicon ID is relatively small compared to the overall programming time.

3. *Bulk Erase*. Erasing the device in-system involves shifting in the instructions to erase the device and applying one erase pulse of 100 ms.

4. *Program*. Programming the device in-system involves shifting in the address and data and then applying the programming pulse to program the EEPROM cells. This process is repeated for each EEPROM address.

5. *Verify*. Verifying an Altera device in-system involves shifting in addresses, applying the read pulse to verify the EEPROM cells, and shifting out the data for comparison. This process is repeated for each EEPROM address.

6. *Exit ISP*. An exit ISP stage ensures that the I/O pins transition smoothly from ISP mode to user mode. The exit ISP stage requires 1 ms.

Programming Times

The time required to implement each of the six programming stages can be broken into the following two elements:

- A pulse time to erase, program, or read the EEPROM cells.
- A shifting time based on the test clock (`TCK`) frequency and the number of `TCK` cycles to shift instructions, address, and data into the device.

By combining the pulse and shift times for each of the programming stages, the program or verify time can be derived as a function of the TCK frequency, the number of devices, and specific target device(s). Because different ISP-capable devices have a different number of EEPROM cells, both the total fixed and total variable times are unique for a single device.

Programming a Single MAX 9000 Device

The time required to program a single MAX 9000 device in-system can be calculated from the following formula:

$$t_{PROG} = t_{PPULSE} + \frac{Cycle_{PTCK}}{f_{TCK}}$$

where: t_{PROG} = Programming time
t_{PPULSE} = Sum of the fixed times to erase, program, and verify the EEPROM cells
$Cycle_{PTCK}$ = Number of TCK cycles to program a device
f_{TCK} = TCK frequency

The ISP times for a stand-alone verification of a single MAX 9000 device can be calculated from the following formula:

$$t_{VER} = t_{VPULSE} + \frac{Cycle_{VTCK}}{f_{TCK}}$$

where: t_{VER} = Verify time
t_{VPULSE} = Sum of the fixed times to verify the EEPROM cells
$Cycle_{VTCK}$ = Number of TCK cycles to verify a device

Figure 11. MAX 9000 JTAG Waveforms

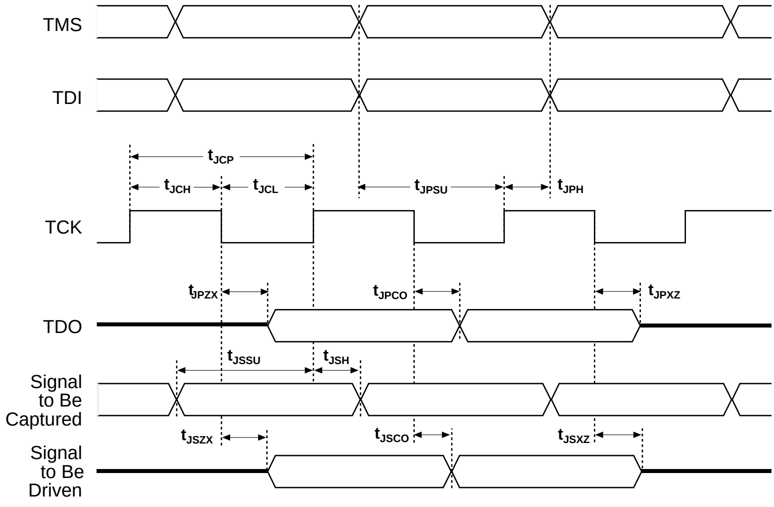


Table 13 shows the JTAG timing parameters and values for MAX 9000 devices.

Table 13. JTAG Timing Parameters & Values for MAX 9000 Devices

Symbol	Parameter	Min	Max	Unit
t_{JCP}	TCK clock period	100		ns
t_{JCH}	TCK clock high time	50		ns
t_{JCL}	TCK clock low time	50		ns
t_{JPSU}	JTAG port setup time	20		ns
t_{JPH}	JTAG port hold time	45		ns
t_{JPCO}	JTAG port clock to output		25	ns
t_{JPZX}	JTAG port high impedance to valid output		25	ns
t_{JPXZ}	JTAG port valid output to high impedance		25	ns
t_{JSSU}	Capture register setup time	20		ns
t_{JSH}	Capture register hold time	45		ns
t_{JSCO}	Update register clock to output		25	ns
t_{JSZX}	Update register high impedance to valid output		25	ns
t_{JSXZ}	Update register valid output to high impedance		25	ns

For detailed information on JTAG operation in MAX 9000 devices, refer to *Application Note 39 (IEEE 1149.1 (JTAG) Boundary-Scan Testing in Altera Devices)*.

Programmable Speed/Power Control

MAX 9000 devices offer a power-saving mode that supports low-power operation across user-defined signal paths or the entire device. Because most logic applications require only a small fraction of all gates to operate at maximum frequency, this feature allows total power dissipation to be reduced by 50% or more.

The designer can program each individual macrocell in a MAX 9000 device for either high-speed (i.e., with the Turbo Bit™ option turned on) or low-power (i.e., with the Turbo Bit option turned off) operation. As a result, speed-critical paths in the design can run at high speed, while remaining paths operate at reduced power. Macrocells that run at low power incur a nominal timing delay adder (t_{LPA}) for the LAB local array delay (t_{LOCAL}).

Design Security

All MAX 9000 EPLDs contain a programmable security bit that controls access to the data programmed into the device. When this bit is programmed, a proprietary design implemented in the device cannot be copied or retrieved. This feature provides a high level of design security, because programmed data within EEPROM cells is invisible. The security bit that controls this function, as well as all other programmed data, is reset only when the device is erased.

Generic Testing

MAX 9000 EPLDs are fully functionally tested. Complete testing of each programmable EEPROM bit and all logic functionality ensures 100% programming yield. AC test measurements are taken under conditions equivalent to those shown in Figure 12. Test patterns can be used and then erased during the early stages of the production flow.

Figure 12. MAX 9000 AC Test Conditions

Power supply transients can affect AC measurements. Simultaneous transitions of multiple outputs should be avoided for accurate measurement. Threshold tests must not be performed under AC conditions. Large-amplitude, fast ground-current transients normally occur as the device outputs discharge the load capacitances. When these transients flow through the parasitic inductance between the device ground pin and the test system ground, significant reductions in observable noise immunity can result. Numbers in parentheses are for 3.3-V outputs. Numbers without parentheses are for 5.0-V devices or outputs.

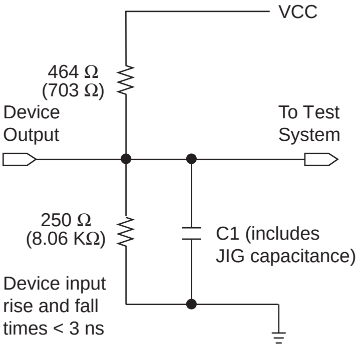


Table 22. MAX 9000 Internal Timing Characteristics *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-10		-15		-20		
			Min	Max	Min	Max	Min	Max	
t_{LAD}	Logic array delay			3.5		4.0		4.5	ns
t_{LAC}	Logic control array delay			3.5		4.0		4.5	ns
t_{IC}	Array clock delay			3.5		4.0		4.5	ns
t_{EN}	Register enable time			3.5		4.0		4.5	ns
t_{SEXP}	Shared expander delay			3.5		5.0		7.5	ns
t_{PEXP}	Parallel expander delay			0.5		1.0		2.0	ns
t_{RD}	Register delay			0.5		1.0		1.0	ns
t_{COMB}	Combinatorial delay			0.4		1.0		1.0	ns
t_{SU}	Register setup time		2.4		3.0		4.0		ns
t_{H}	Register hold time		2.0		3.5		4.5		ns
t_{PRE}	Register preset time			3.5		4.0		4.5	ns
t_{CLR}	Register clear time			3.7		4.0		4.5	ns
t_{FTD}	FastTrack drive delay			0.5		1.0		2.0	ns
t_{LPA}	Low-power adder	*(5)*		10.0		15.0		20.0	ns

Table 24. Interconnect Delays

Symbol	Parameter	Conditions	Speed Grade						Unit
			-10		-15		-20		
			Min	Max	Min	Max	Min	Max	
t_{LOCAL}	LAB local array delay			0.5		0.5		0.5	ns
t_{ROW}	FastTrack row delay	(6)		0.9		1.4		2.0	ns
t_{COL}	FastTrack column delay	(6)		0.9		1.7		3.0	ns
t_{DIN_D}	Dedicated input data delay			4.0		4.5		5.0	ns
t_{DIN_CLK}	Dedicated input clock delay			2.7		3.5		4.0	ns
t_{DIN_CLR}	Dedicated input clear delay			4.5		5.0		5.5	ns
t_{DIN_IOC}	Dedicated input I/O register clock delay			2.5		3.5		4.5	ns
t_{DIN_IO}	Dedicated input I/O register control delay			5.5		6.0		6.5	ns

Notes to tables:

(1) These values are specified under the MAX 9000 device recommended operating conditions, shown in Table 15 on page 27.

(2) See *Application Note 77 (Understanding MAX 9000 Timing)* for more information on test conditions for $\mathbf{t_{PD1}}$ and $\mathbf{t_{PD2}}$ delays.

(3) This parameter is a guideline that is sample-tested only. It is based on extensive device characterization. This parameter applies for both global and array clocking as well as both macrocell and I/O cell registers.

(4) Measured with a 16-bit loadable, enabled, up/down counter programmed in each LAB.

(5) The t_{LPA} parameter must be added to the t_{LOCAL} parameter for macrocells running in low-power mode.

(6) The t_{ROW}, t_{COL}, and t_{IOC} delays are worst-case values for typical applications. Post-compilation timing simulation or timing analysis is required to determine actual worst-case performance.

Power Consumption

The supply power (P) versus frequency ($\mathbf{f_{MAX}}$) for MAX 9000 devices can be calculated with the following equation:

$$P = P_{INT} + P_{IO} = I_{CCINT} \times V_{CC} + P_{IO}$$

The P_{IO} value, which depends on the device output load characteristics and switching frequency, can be calculated using the guidelines given in *Application Note 74 (Evaluating Power for Altera Devices)*. The I_{CCINT} value depends on the switching frequency and the application logic.

The I_{CCINT} value is calculated with the following equation:

$$I_{CCINT} = (A \times MC_{TON}) + [B \times (MC_{DEV} - MC_{TON})] + (C \times MC_{USED} \times \mathbf{f_{MAX}} \times \mathbf{tog_{LC}})$$

Figure 15. I_{CC} vs. Frequency for MAX 9000 Devices (Part 1 of 2)

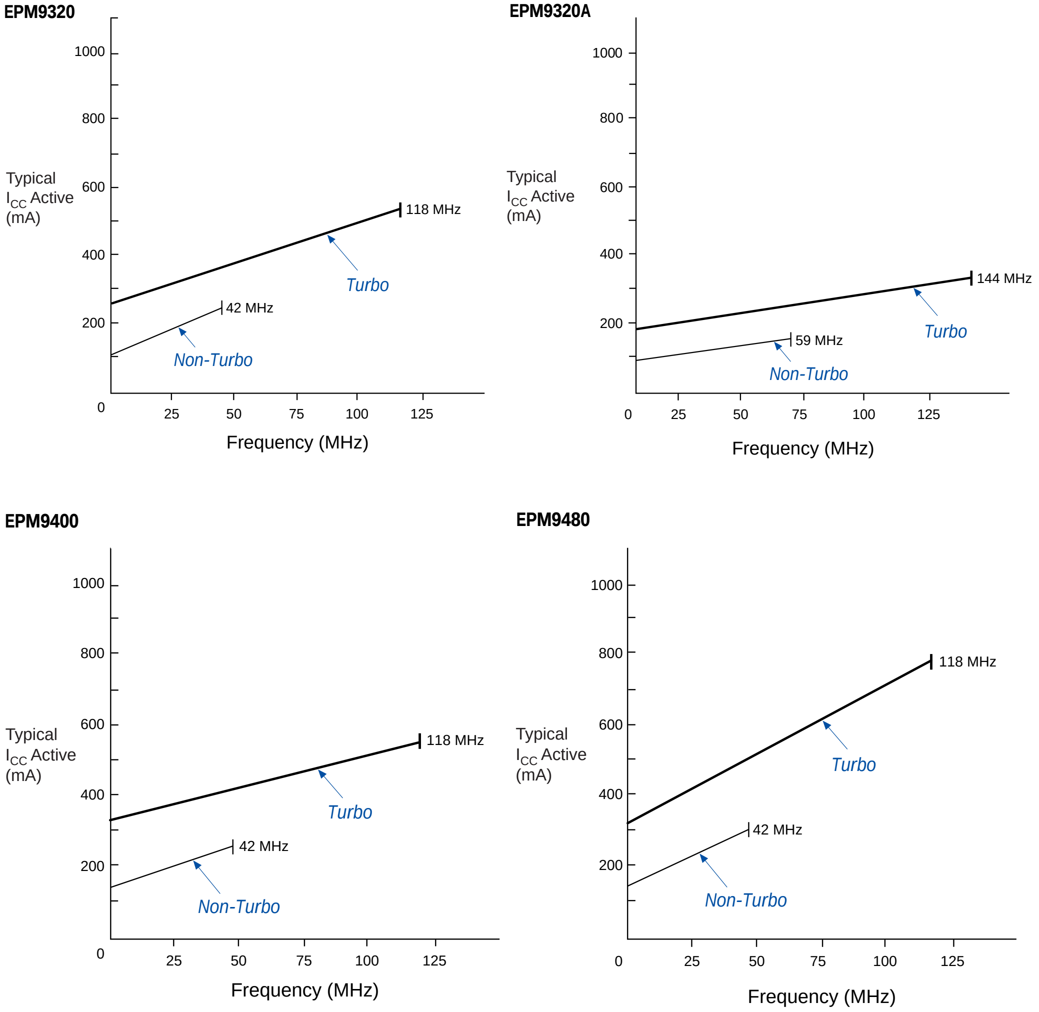


Table 26. EPM9320 & EPM9320A Dedicated Pin-Outs (Part 2 of 2) *Note (1)*

Pin Name	**84-Pin PLCC** *(2)*	**208-Pin RQFP**	**280-Pin PGA** *(3)*	**356-Pin BGA**
`GND`	6, 18, 24, 25, 48, 61, 67, 70	14, 20, 24, 31, 35, 41, 42, 43, 44, 46, 47, 66, 85, 102, 110, 113, 114, 115, 116, 118, 121, 122, 132, 133, 143, 152, 170, 189, 206	D4, D5, D16, E4, E5, E6, E15, E16, F5, F15, G5, G15, H5, H15, J5, J15, K5, K15, L5, L15, M5, M15, N5, N15, P4, P5, P15, P16, R4, R5, R15, R16, T4, T5, T16	A9, A22, A25, A26, B25, B26, D2, E1, E26, F2, G1, G25, G26, H2, J1, J25, J26, K2, L26, M26, N1, N25, P26, R2, T1, U2, U26, V1, V25, W25, Y26, AA2, AB1, AB26, AC26, AE1, AF1, AF2, AF4, AF7, AF20
`VCCINT` (5.0 V only)	14, 21, 28, 57, 64, 71	10, 19, 30, 45, 112, 128, 139, 148	D15, E8, E10, E12, E14, R7, R9, R11, R13, R14, T14	D26, F1, H1, K26, N26, P1, U1, W26, AE26, AF25, AF26
`VCCIO` (3.3 or 5.0 V)	15, 37, 60, 79	5, 25, 36, 55, 72, 91, 111, 127, 138, 159, 176, 195	D14, E7, E9, E11, E13, R6, R8, R10, R12, T13, T15	A1, A2, A21, B1, B10, B24, D1, H26, K1, M25, R1, V26, AA1, AC25, AF5, AF8, AF19
No Connect (N.C.)	29	6, 7, 8, 9, 11, 12, 13, 15, 16, 17, 18, 109, 140, 141, 142, 144, 145, 146, 147, 149, 150, 151	B6, K19, L2, L4, L18, L19, M1, M2, M3, M4, M16, M17, M18, M19, N1, N2, N3, N4, N16, N17, N18, N19, P1, P2, P3, P17, P18, P19, R1, R2, R3, R17, R18, R19, T1, T2, T3, T17, T18, T19, U1, U2, U3, U17, U18, U19, V1, V2, V19, W1	B4, B5, B6, B7, B8, B9, B11, B12, B13, B14, B15, B16, B18, B19, B20, B21, B22, B23, C4, C23, D4, D23, E4, E22, F4, F23, G4, H4, H23, J23, K4, L4, L23, N4, P4, P23, R3, R26, T2, T3, T4, T5, T22, T23, T24, T25, T26, U3, U4, U5, U22, U23, U24, U25, V2, V3, V4, V5, V22, V23, V24, W1, W2, W3, W4, W5, W22, W23, W24, Y1, Y2, Y3, Y4, Y5, Y22, Y23, Y24, Y25, AA3, AA4, AA5, AA22, AA23, AA24, AA25, AA26, AB2, AB3, AB4, AB5, AB23, AB24, AB25, AC1, AC2, AC23, AD4, AD23, AE4, AE5, AE6, AE7, AE9, AE11, AE12, AE14, AE15, AE16, AE18, AE19, AE20, AE21, AE22, AE23
VPP *(4)*	56	48	C4	E25
Total User I/O Pins *(5)*	60	132	168	168

Table 29. EPM9560 & EPM9560A Dedicated Pin-Outs (Part 2 of 2) *Note (1)*

Pin Name	208-Pin RQFP	240-Pin RQFP	280-Pin PGA *(2)*	304-Pin RQFP *(2)*	356-Pin BGA
No Connect (N.C.)	109	–	B6, W1	1, 2, 76, 77, 78, 79, 80, 81, 82, 83, 84, 145, 146, 147, 148, 149, 150, 151, 152, 153, 154, 227, 228, 229, 230, 231, 232, 233, 234, 235, 236, 297, 298, 299, 300, 301, 302, 303, 304	B4, B5, B6, B7, B8, B9, B11, B12, B13, B14, B15, B16, B18, B19, B20, B21, B22, B23, C4, C23, D4, D23, E4, E22, F4, F23, G4, H4, H23, J23, K4, L4, L23, N4, P4, P23, T4, T23, U4, V4, V23, W4, Y4, AA4, AA23, AB4, AB23, AC23, AD4, AD23, AE4, AE5, AE6, AE7, AE9, AE11, AE12, AE14, AE15, AE16, AE18, AE19, AE20, AE21, AE22, AE23
VPP *(3)*	48	67	C4	75	E25
Total User I/O Pins *(4)*	153	191	216	216	216

Notes:

(1) All pins not listed are user I/O pins.

(2) EPM9560A devices are not offered in this package.

(3) During in-system programming, each device's VPP pin must be connected to the 5.0-V power supply. During normal device operation, the VPP pin is pulled up internally and can be connected to the 5.0-V supply or left unconnected.

(4) The user I/O pin count includes dedicated input pins and all I/O pins.

Revision History

Information contained in the *MAX 9000 Programmable Logic Device Family Data Sheet* version 6.5 supersedes information published in previous versions.

Version 6.5

Version 6.6 of the *MAX 9000 Programmable Logic Device Family Data Sheet* contains the following change:

- Added Tables 7 through 9.
- Added "Programming Sequence" on page 20 and "Programming Times" on page 20

Version 6.4

Version 6.4 of the *MAX 9000 Programmable Logic Device Family Data Sheet* contains the following change: Updated text on page 23.

Version 6.3

Version 6.3 of the *MAX 9000 Programmable Logic Device Family Data Sheet* contains the following change: added Note (7) to Table 16.

101 Innovation Drive
San Jose, CA 95134
(408) 544-7000
http://www.altera.com
Applications Hotline:
(800) 800-EPLD
Customer Marketing:
(408) 544-7104
Literature Services:
lit_req@altera.com

Copyright © 2003 Altera Corporation. All rights reserved. Altera, The Programmable Solutions Company, the stylized Altera logo, specific device designations, and all other words and logos that are identified as trademarks and/or service marks are, unless noted otherwise, the trademarks and service marks of Altera Corporation in the U.S. and other countries. All other product or service names are the property of their respective holders. Altera products are protected under numerous U.S. and foreign patents and pending applications, maskwork rights, and copyrights. Altera warrants performance of its semiconductor products to current specifications in accordance with Altera's standard warranty, but reserves the right to make changes to any products and services at any time without notice. Altera assumes no responsibility or liability arising out of the application or use of any information, product, or service described herein except as expressly agreed to in writing by Altera Corporation. Altera customers are advised to obtain the latest version of device specifications before relying on any published information and before placing orders for products or services.

I.S. EN ISO 9001

Printed on Recycled Paper.